PATENT ASSIGNMENT COVER SHEET

Electronic Version v1.1 Stylesheet Version v1.2 EPAS ID: PAT6446386

SUBMISSION TYPE:	NEW ASSIGNMENT
NATURE OF CONVEYANCE:	SECURITY INTEREST GRANT INTELLECTUAL PROPERTY

CONVEYING PARTY DATA

Name	Execution Date
QUANTRONIX, INC.	12/10/2020

RECEIVING PARTY DATA

Name:	JPMORGAN CHASE BANK, N.A.
Street Address:	10 SOUTH DEARBORN, FLOOR L2, IL1-1145
City:	CHICAGO
State/Country:	ILLINOIS
Postal Code:	60603

PROPERTY NUMBERS Total: 6

Property Type	Number
Patent Number:	RE42430
Patent Number:	D490328
Patent Number:	8928896
Patent Number:	9528813
Patent Number:	9435637
PCT Number:	US2019014751

CORRESPONDENCE DATA

Fax Number: (617)523-6850

Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent

using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.

Phone: 617-523-2700

Email: susan.dinicola@hklaw.com,cynthia.duntz@hklaw.com

Correspondent Name: HOLLAND & KNIGHT LLP Address Line 1: 10 ST. JAMES AVENUE

Address Line 4: BOSTON, MASSACHUSETTS 02116

ATTORNEY DOCKET NUMBER:	088499.01388
NAME OF SUBMITTER:	SUSAN C. DINICOLA
SIGNATURE:	/Susan C. DiNicola/
DATE SIGNED:	12/11/2020

Total Attachments: 12

PATENT REEL: 055087 FRAME: 0001

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SECURITY INTEREST GRANT INTELLECTUAL PROPERTY

This Security Interest Grant Intellectual Property (as the same may be amended, restated, supplemented or otherwise modified from time to time, the "Grant"), is entered into as of December 10, 2020, by and between Quantronix, Inc., a Utah corporation ("Quantronix") in favor of JP Morgan Chase Bank, N.A. ("Lender"). Quantronix is referred to herein as a "Grantor." Capitalized terms used herein but not otherwise defined shall have the meaning set forth in the Credit Agreement (as defined below).

WHEREAS, the Grantor and the Lender have entered into that certain Credit Agreement, dated as of the date hereof by and between the Lender, the Grantor, and the other Loan Parties from time to time party thereto (the "<u>Credit Agreement</u>");

WHEREAS, and the Grantor and the Lender have entered into a Pledge and Security Agreement, dated as of the date hereof, with any additional entities become parties thereto (as amended, restated, supplemented or otherwise modified from time to time, respectively the "Security Agreement"); and

WHEREAS, pursuant to the terms of the Credit Agreement and the Security Agreement, Grantor created in favor of the Lender a security interest in, and the Lender has become a secured creditor with respect to, all assets of Grantor, which includes the Intellectual Property Collateral (as defined below);

WHEREAS, the Grantor has adopted, used and is using, and holds all right, title and interest in various intangible assets, including the Intellectual Property Collateral (as defined below);

NOW, THEREFORE, for good and valuable consideration, the receipt and adequacy of which are hereby acknowledged, Grantor hereby grants to the Lender a security interest in all of Grantor's right, title and interest in and to the following (the "Intellectual Property Collateral"):

- (A) the patents and patent applications set forth in <u>Schedule A</u> hereto (the "*Patents*");
- (B) the trademark and service mark registrations and applications set forth in <u>Schedule B</u> hereto (provided that no security interest shall be granted in United States intent-to-use trademark applications to the extent that, and solely during the period in which, the grant of a security interest therein would impair the validity or enforceability of such intent-to-use trademark applications under applicable federal law), together with the goodwill symbolized thereby (the "*Trademarks*");
- (C) all copyrights, whether registered or unregistered, now owned or hereafter acquired by Grantor, including, without limitation, the copyright registrations and applications set forth in Schedule C hereto (the "Copyrights");

- (D) all reissues, divisions, continuations, continuations-in-part, extensions, renewals and reexaminations of any of the foregoing, and, to the extent applicable, all rights in the foregoing provided by international treaties or conventions, all rights corresponding thereto throughout the world and all other rights of any kind whatsoever of Grantor accruing thereunder or pertaining thereto;
- (E) any and all claims for damages and injunctive relief for past, present and future infringement, dilution, misappropriation, violation, misuse or breach with respect to any of the foregoing, with the right, but not the obligation, to sue for and collect, or otherwise recover, such damages; and
- (F) any and all proceeds of, collateral for, income, royalties and other payments now or hereafter due and payable with respect to, and supporting obligations relating to, any and all of the Collateral of or arising from any of the foregoing.

Grantor does hereby further acknowledges and affirms that the rights and remedies of the Lender with respect to the Intellectual Property Collateral, are more fully set forth in the Credit Agreement and Security Agreement, the terms and provisions of which are hereby incorporated herein by reference as if fully set forth herein.

The Credit Agreement, Security Agreement and this Grant shall be construed in accordance with and governed by the laws of the State of New York applicable to contracts made and to be performed entirely within such State. Whenever possible, each provision of the Credit Agreement, Security Agreement and the Grant shall be interpreted in such manner as to be effective and valid under applicable law, but if any provision of the Credit Agreement, Security Agreement or the Grant, shall be prohibited by or invalid under applicable law, such provision shall be ineffective to the extent of such prohibition or invalidity, without invalidating the remainder of such provision or the remaining provisions of the Credit Agreement, Security Agreement or the Grant.

(Signature Page Follows)

QUANTRONIX, INC., a Utah corporation

Clark Skeen Treasurer

[Signature Page to Intellectual Property Security Agreement]

PATENT

REEL: 055087 FRAME: 0005

Schedule A

Patents and Patent Applications

<u>Patent</u>	Number	<u>Date</u>	Country	Owner/Assignee
Dimensioning System and Method of Dimensioning (Cubiscan 150)	2,509,504	1/20/2004 (date filed) 01/31/2006 (date granted)	Canada	Quantronix, Inc.
Dimensioning System and Method of Dimensioning	12/496,227 / RE42,430	7/1/2009 (date filed) 06/07/2011 (date granted)	<u>us</u>	Quantronix, Inc.
Dimensioning System	29/175,624 / D490,328	02/07/2003 (date filed) 05/25/2004 (date granted)	<u>US</u>	Quantronix, Inc.
Object Dimensioning System and Related Methods	13/366,901 / 8,928,896	2/06/2012 (date filed)	<u>us</u>	Quantronix, Inc.

[Signature Page to Intellectual Property Security Agreement]

REEL: 055087 FRAME: 0006

		01/06/2015 (date granted)		
<u>Object</u>	14/308,333 /	06/18/2014 (date	<u>US</u>	Quantronix, Inc.
<u>Dimensioning</u>	<u>9,528,813</u>	<u>filed)</u>		
Apparatus,				
Systems and				
Related Methods		12/27/2016 (date		
		granted)		
Conveyorized	14/631,517 /	2/25/2015 (date	US	Quantronix, Inc.
Object	9,435,637	filed)		<u> </u>
Dimensioning				
System and				
Related Methods		09/06/2016 (date		
		issued		
<u>Illuminated</u>	US2019/014751	1/23/2019 (date	<u>US</u>	Quantronix, Inc.
Markers for		<u>filed)</u>		
<u>Vehicle</u>				
Identification and				
Monitoring and				
Related Systems				
and Methods				
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Schedule B

Trademark and Service Mark Registrations and Applications

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Quantronix Trademarks - Status Report October 20:

TMESERGE	TM3382US	TM3382MMTH	TM3382MMRU	TM3382MMMX	TM3382MMKR	TM3382MMIP	NIMM2855ML	EDMN28EEMT	TM3382MMEM	TM3382MMCN	TM3382MM	TM3382CA	TM3138RU	TM1139AD	SUIESML	TMS91CT	TM591CA	TMESIAL	TMS91.1CA	SHOGEMA	тмеераці	Matter Code
CANADA	UNITED STATES	THAILAND	FEDERATION OF PUSSIA	MEXICO	REPUBLIC OF KOREA	JAPAN	INDIA	ONLIED KINGDOM	COMMUNITY (CIM)	CHINA	OdIM	CANADA	RUSSIA	AUSTRALIA	UNITED STATES	COMMUNITY (CTM)	CANADA	AUSTRALIA	CANADA	UNITED STATES	AUSTRALIA	Country
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08/17/2017	08/07/2017	02/56/2018	8702/90/20	02/06/2018	02/06/2018	02/55/2018	02/06/2018	02/06/2018	02/06/2018	02/06/2018	02/06/2018 1,4	08/17/2017	11/05/2014 582	05/08/1996 708		10/24/1996 360	01/14/1994 TM/	05/08/1996 708197	12/04/2009 TM/	05/17/1990 1,6	٠,١	File Date Be
											1,402,646 02/06/2018		582,071 07/26/2016	708158 55/08/1996	50	360776 06/29/1999	TMA441,551 03/31/1995	3861/80/50	TM4808,849 10/12/2011	1,840,327 04/09/1991		Reg No. Reg Date
Pariding	Registered	Pending	Pending	Panding	Registered	Pending	Pending	Registered	Pending	Registered	18 Registered - February 6, 2028: Renewal Due	Pending - October 11, 2019: Response Office Action Due	16 Registered - November 5, 2024: Renewal Due	000000000	1	99 Registered - October 24, 2026: Renewal Due		96 Registered - May 8, 2026: Renewal Di	11 Registered - October 12, 2026: Renewal Due	51 Registered - April 9, 2021: Penewat Due		Seg. No. Reg Date Action due: 2020
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Forcel and bulk material measurement systems comprised of ultrasonic sensors and meters. Apparetus for weighing percei and bulk material; apperatus for meters, Apparetus for weighing percei and bulk material measurement system comprised of lasers; pancel and bulk material measurement system comprised of lasers; pancel and bulk material measurement system comprised of an L.E.D., array, pancel and bulk material measurement system comprised of on Gameras.	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring pancel and bulk material	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring parcel and bulk material:	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring parcel and built material	Software for use with an apparatus for weighing and measuring parcel and bulk maferial	Software for use with an apparatus for weighing and measuring pantel and bulk material	Software for use with an apparatus for weighing and measuring parcel and bulk material	Software for use with an apparatus for weighing and measuring pancel and bulk material	Instruments and instruments for weighing, equipped with ultrasoric sensors and counters; Measuring instruments equipped with ultrasonic sensors and counters; Instrumentation electrical, equipped with ultrasonic sensors and meters, instrumentation and measurement, equipped with ultrasonic sensors and counters; precision measuring instruments, equipped with ultrasonic sensors and counters. (English translation provided by Godgle translate)	Parcel and bulk material measurement systems comprised of ultrasonic, sensors and meters	Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters	Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters	Electrical, scientific and teaching apparatus and software	Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters	Electrical, scientific and teaching apparatus and software	Parcel and fulk material measurement systems comprised of ultrasoric sensors and meters	Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters	Class description

Quantronix Trademarks - Status Report October 2020

TM3383MMKR	ТМЗЗӨЗМКІР	MWEBSEML	TM3383MMGB	ТМЗЗВЗММЕМ	TM32836MMCN	TM3383.2CN	Massas Code TM3383MM
REPUBLIC OF KOREA	Japan	INDIA	LWITED KINGDOM	EUROPEAN COMMUNITY (CTM)	CHINA	CHINA	Committy
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12/04/2017	12/94/2017	12/04/2017	12/04/2017	12/04/2017	12/04/2017	02/02/2019	File Date 12/04/2017
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							Rag Date 12/04/2017
% egistered	Registered - December 4, 2017	Pending	Registered - December 4, 2027: Pariewal I Due	Registered	Rending	Pending	.398.345 12/04/2017 Registered - December 4, 2027; Renewal due
600	900	009	920	009	999		398 Class
Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk material; apparatus for measuring the order physical dimensions of parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an LE.D. array for measuring duter physical dimensions; parcel and bulk material measurements system comprised of our control of the property of the party of the property of the party of the parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions:	Parciel and dulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parciel and bulk material; apparatus for measuring the outer physical dimensions of parciel and bulk material; parciel and bulk material measurement system comprised of lesens; parciel and bulk material measurement system comprised of an LE D, array for measuring outer physical dimensions; parciel and bulk material measurement system comprised of cameras for measuring outer physical dimensions; parciel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Fercel and bulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of barcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; parcel and bulk material measurement system controlled of an LED, array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Plancial and bulk material measurement systems comprised of ultrascolo sensors and meters; apparatus for weighing parcial and bulk material; apparatus for measuring the outer physical dimensions of parcial and bulk material; parcial and bulk material measurement system comprised of leasers; parcial and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcial and bulk material measurement system consprised of cameras for measuring outer physical dimensions.	Parcel and bulk material measurement systems comprised of ultrasonic sensors and materia; apparatus for weighing parcel and bulk material; apparatus for measuring the other physical dimensions of pancel and bulk material measurement system comprised of an Lasers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system controlled outer material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions	Plances and bulk material ineasurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk material, apparatus for measuring the outer physical dimensions of parcel and bulk material measurement system comprised of an lasers; parcel and bulk material measurement system comprised of an LE-D, enray for measuring outer physical dimensions; parcel and bulk material measurement system comprised of an LE-D, enray for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Computer programs [downloadable software]; Computer software, recorded; Data processing apparatus; Scanners [data processing equipment]; Meters; Quantity indicators; Weighing apparatus and instruments; automatic measuring instrument; Measures; Skins (Apparatus for measuring the thickness of -); Rulers [measuring instruments]; measuring gauge; Contents of Measuring apparatus; Surveying apparatus and instruments; Precision measuring apparatus; Measuring instruments; sensor; Camcorders"	Class description Farce and bulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk material; apparatus for weighing parcel and bulk material; parcel and bulk material measurement system comprised of an lasers; parcel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.

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Registered - December 4, 2017; Renewal			3 June 2019		Registered - April 17, 2024: Sections 8 15 Declaration due					
009	000000000000000000000000000000000000000			009	b. 009	009	000			Intl Class
parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array; parcel and bulk material measurement experience of comprised of cameras. Apparatus for weighing parcel and bulk material, apparatus for measuring the other physical dimensions of parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of an L.E.D. array for measurement system comprised of cameras for measuring outer physical dimensions.	Apparatus for weighing period and bulk material; apparatics by measuring the outer physical dimensions of paned and bulk material; parcel and bulk material measurement system comprised of lasers, parcel and bulk material measurement system comprised of an L.E.D. array for measurement system comprised of an L.E.D. array for measurement system comprised of an L.E.D. array for measurement system comprised of outer physical dimensions; parcel and bulk material integrating content physical dimensions; parcel and bulk material integrative for consecutions.	Apparatus for weighing parcel and bulk material; apparatus for measuring parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array; parcel and bulk material measurement system comprised of cameras	Plancial and bulk material measurement systems contribed of ultrascoric sensors and meters; apparatus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of parcel and bulk material; parcel and bulk material measurement system comprised of losers; parcel and bulk material measurement system comprised of an	Parcel and bulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk material; apparatus for measuring the puter physical dimensions of parcel and bulk material measurement system comprised of material; parcel and bulk material measurement system comprised of all lesers; parcel and bulk material measurement system comprised of an	Apparatus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system.	Plancel and bulk material measurement systems comprised of ultrasoric sensors and meters, apparatus for weighing parcel and bulk material; sensors and meters, apparatus for weighing parcel and bulk material apparatus for measuring the outer physical dimensions of parcel and bulk material measurement system comprised of materials, parcel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; parcel and bulk materials measurement system comprised of the measuring outer physical dimensions; parcel and bulk	Farcel and bulk material measurement systems comprised of ultrascoric sensors and meters; apparatus for weighing parcel and bulk material; apparatus for meighing parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of m. LE.D. array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of carnetas for measuring outer physical dimensions.	Fercel and bulk material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing pareal and bulk material; apparatus for weighing pareal and bulk material; pareal and bulk material; pareal and bulk material measurement system comprised of lasers; percel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; pareal and bulk material measurement system comprised of carneras for measuring outer physical dimensions.	Parcel and bulk material measurement systems comprised of ultrasonic sensors and more material measurement systems comprised of ultrasonic sensors and meters; apparatus for weighing parcel and bulk materials apparatus for measuring the union physical dimensions of pointel and bulk materials measurement system comprised of lasers; parcel and bulk material measurement system comprised of an LED, array for measuring outer physical dimensions; parcel and bulk materials incasurement system comprised of cameras for measuring outer physical dimensions.	Class description
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Quantronix Trademarks - Status Report October 2020

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THAILAND	FEDERATION OF RUSSIA	MEX100	REPUBLIC OF KOREA	JAPAN	INDXA	UNITED KINGDOM	EUROPEAN COMMUNITY (CTM)	CHINA	Country
N.		3		3		1		0	Mark
1,389,635	1,389,655	1,389,655	1,389,655	1.389.655	1,389,655	1,389,655	1,389,655	1,389,655	Appi. No.
12/04/2017	12/04/2017	12/04/2617	12/04/2017	12/04/2017	12/04/2017	12/04/2017 13	12/04/2017	12/04/2017	2000
						1309655 12/04/2017			Reg No. Reg Date
Pending	Registered	Registered - File Statement of use 02/2022	Registered - December 4, 2017	Registered - December 4, 2017	Reg istered	2017 Registered - December 4, 2027: Renewal Due	Pending - June 16, 2018: Opposition E	Pending	late Action due
009	009	600	909	იიყ	600	newai 009	Ends 009	009	Intl Class
Apparatus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of parcel and bulk material; parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions.	Apparatus for weighing parcal and bulk material; apparatus for measuring the outer physical dimensions of parcal and bulk material; parcal and bulk material; parcal and bulk material measurement system comprised of easers; parcal and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcal and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Apparatus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of parcel and bulk material; parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an LE 0, array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Apparetus for weighing parcel and bulk material; apparatus for measuring the outer physical dimensions of parcel and bulk material; parcel and bulk material measurement system comprised of lasers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcel and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Apparatus for weighing pancel and bulk material, apparatus for measuring the other physical dimensions of pancel and bulk material; parcel and bulk material measurement system comprised of lasers; pancel and bulk material measurement system comprised of as L.E.D. array for measuring outer physical dimensions; pancel and bulk material measurement system comprised of carriers of cameras for measuring outer physical dimensions.	Apparatus for weighing parcial and bulk material; apparatus for measuring the outer physical dimensions of parcial and bulk material; parcial and bulk material measurement system comprised of lasers; parcial and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcial and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Apparatus for weighing pancel and bulk material; apparatus for measuring the outer physical dimensions of pancel and bulk material; pancel and bulk material measurement system comprised of lasers; pancel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; pancel and bulk material measurement system comprised of carriers for measuring outer physical dimensions.	Apparatus for weighing parcal and bulk material; apparatus for measuring the outer physical dimensions of parcal and bulk material; parcal and bulk material measurement system comprised of lasers; parcal and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; parcal and bulk material measurement system comprised of cameras for measuring outer physical dimensions.	Apparatus for weighting parcel and bulk material; apparatus for measuring the outer physical dimensions of pancel and bulk material measurement system comprised of basers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; pancel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; pancel and bulk material measurement system comprised of carneras for measuring outer physical dimensions.	Class description

TM3465MX	TM3384US	Matter Code Country
MEXICO	UNITED STATES	Country
MCUBIBCAN 795722		Mark
795722	87/559,155	Appi. No.
07/21/2006 953366	08/07/2017	File Date
09/20/2006		Reg. No. Reg Date
Registered - July 21, 2026: Renewal Due 009	Pending - September 27, 2018: Statement of Use	Action due
900	009	Inti Class
APPARATUS AND SCIENTIFIC, NAUTICAL, TOPOGRAPHIC	Apparatus for weighting bancel and bulk material; apparatus for measuring the other physical dimensions of pancel and bulk material parcel and bulk material measurement system comprised of basers; parcel and bulk material measurement system comprised of an L.E.D. array for measuring outer physical dimensions; pancel and bulk material measurement system comprised of carmeras for measuring outer physical dimensions.	Intl Class Class description

antronix Trademarks - Status Report October 2020

Schedule C

Copyrights

<u>Copyright</u>	<u>Number</u>	<u>Date</u>	Country	<u>Owner</u>
None				

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RECORDED: 12/11/2020